

<b>Notice of References Cited</b>	Application/Control No. 10/635,344	Applicant(s)/Patent Under Reexamination DELAHOY ET AL.	
	Examiner Steven H. VerSteege	Art Unit 1753	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,150,030	11-2000	Stollenwerk et al.	428/432
	B	US-5,889,295	03-1999	Rennie et al.	257/96
	C	US-5,810,982	09-1998	Sellers, Jeff C.	204/298.08
	D	US-			
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	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	Q					
	R					
	S					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Vossen et al., "Thin Film Processes", pg. 48-49 (1978)
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	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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